

Notice of References Cited	Application/Control No. 09/872,362		Applicant(s)/Patent Under Reexamination CRUPI ET AL.	
	Examiner Anil Khatri		Art Unit 2193	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,877,153	04-2005	Konniersman, Paul M.	717/100
X	B	US-6,898,791	05-2005	Chandy et al.	719/314
X	C	US-6,854,107	02-2005	Green et al.	717/117
X	D	US-6,842,906	01-2005	Bowman-Amuah, Michel K.	719/330
X	E	US-6,550,057	04-2003	Bowman-Amuah, Michel K.	717/126
X	F	US-6,484,310	11-2002	Przybylski et al.	717/101
X	G	US-6,134,706	10-2000	Carey et al.	717/102
X	H	US-5,930,512	07-1999	Boden et al.	717/102
X	I	US-6,550,057	04-2003	Bowman-Amuah, Michel K.	717/126
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hannemann et al, "Design pattern implementation in Java and AspectJ", ACM OOPSLA, pp 161-173, Nov. 2002
	V	Mapelsden et al, "Design pattern and instantiating using DPML", ACM, Australian Com. Soc. TOOLS, vol. 10, pp 3-11, 2002
	W	Mak et al, "Precise modeling of design patterns in UML", IEEE ICSE, pp 252-261, 2004
	X	Noble et al, "Metaphor and metonymy in object oriented design patterns", ACM ACS, vol. 4, pp 187-195, 2001

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.